Fig. 1

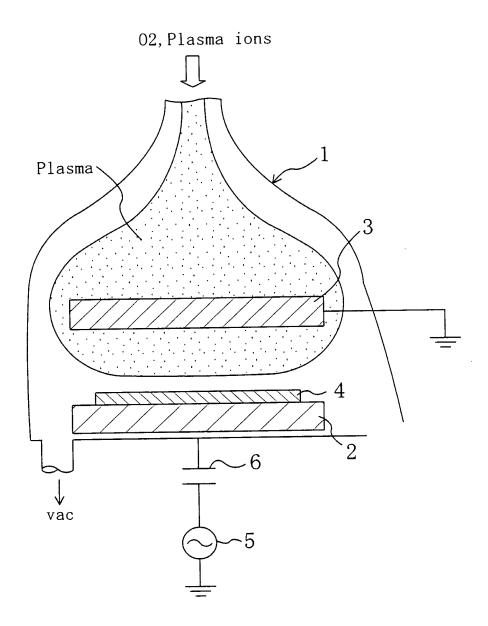


Fig.2(a)

Dependency of film thickness on plasma time

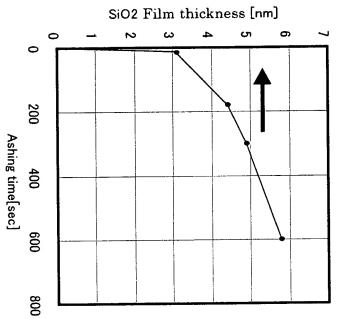
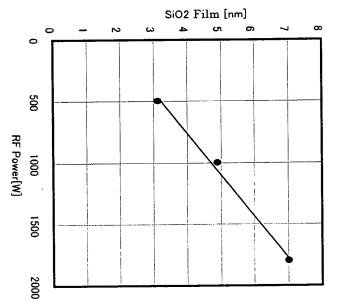


Fig.2(b)

Dependency of film thickness on bias



Time	Te	곢	任丑	02	ဂ္ဂ
ne	Temp	RF Power	מ		Conditions
5[min]	180[°C]	500[W]	66[Pa]	800[ml/min]	
5[min]	180[°C]	1000[W]	66[Pa]	800[ml/min]	
5[min]	180[°C]	1800[w]	66[Pa]	800[ml/min]	

Pressure [pa]

High frequency power [W]

1000

Oxygen flow rate [ml/min]

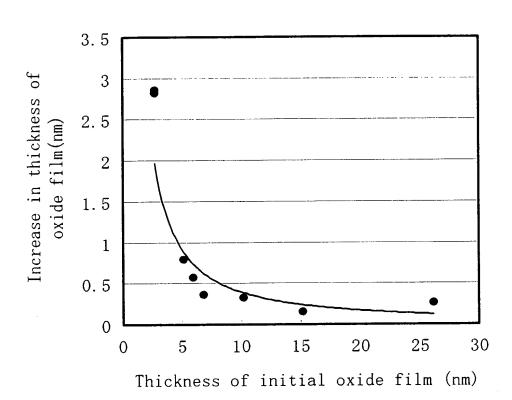
800

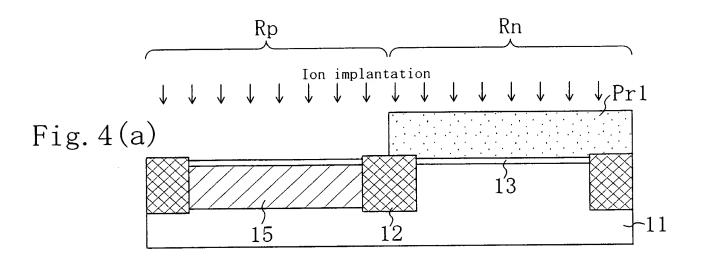
66

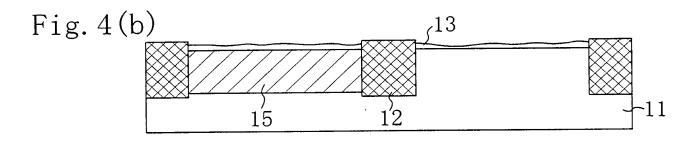
Temperature [°C]

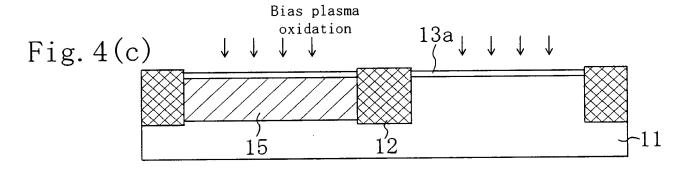
Time [sec]

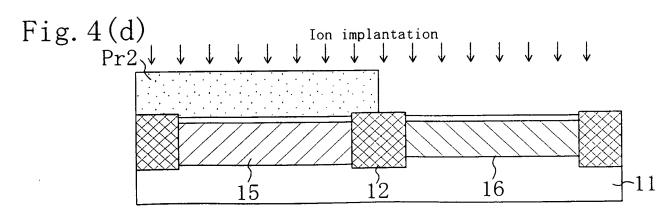
Fig. 3

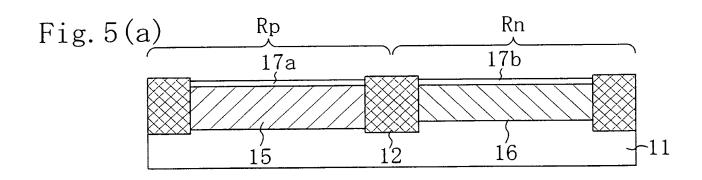


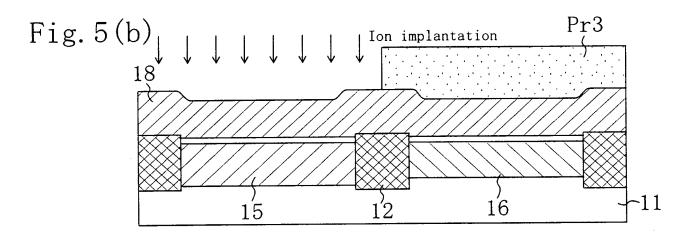


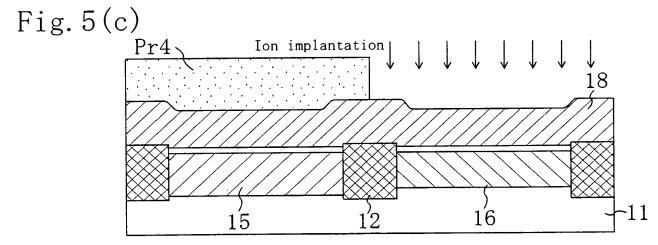


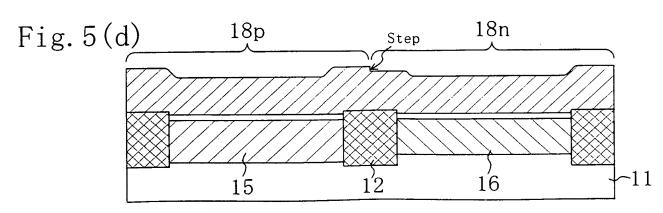


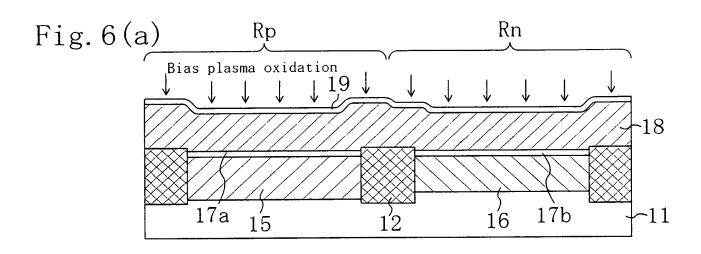


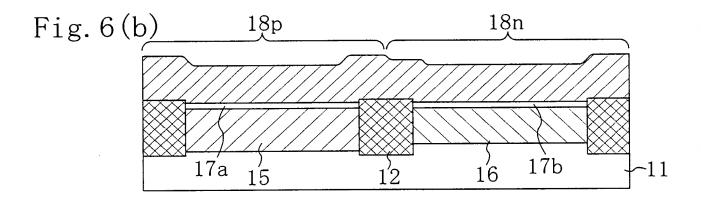


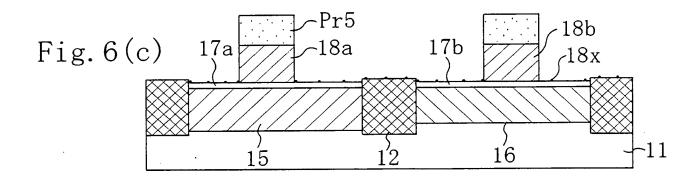


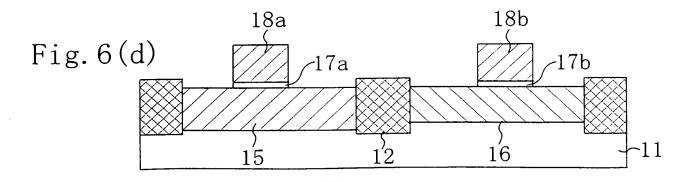


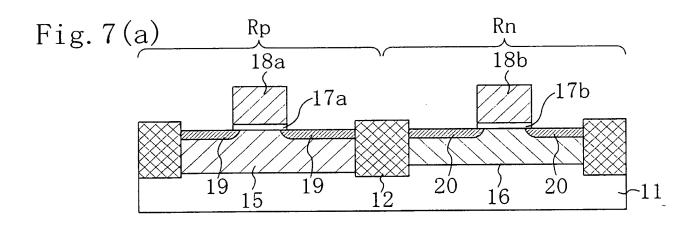


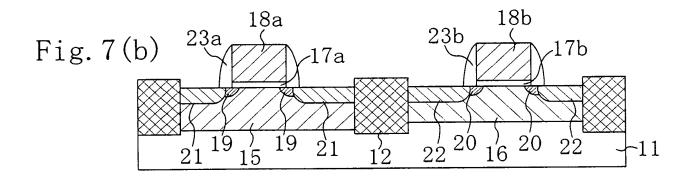


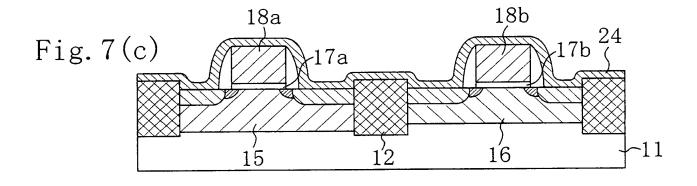


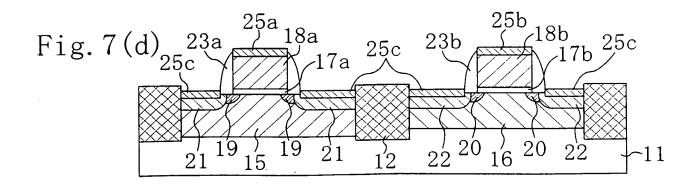


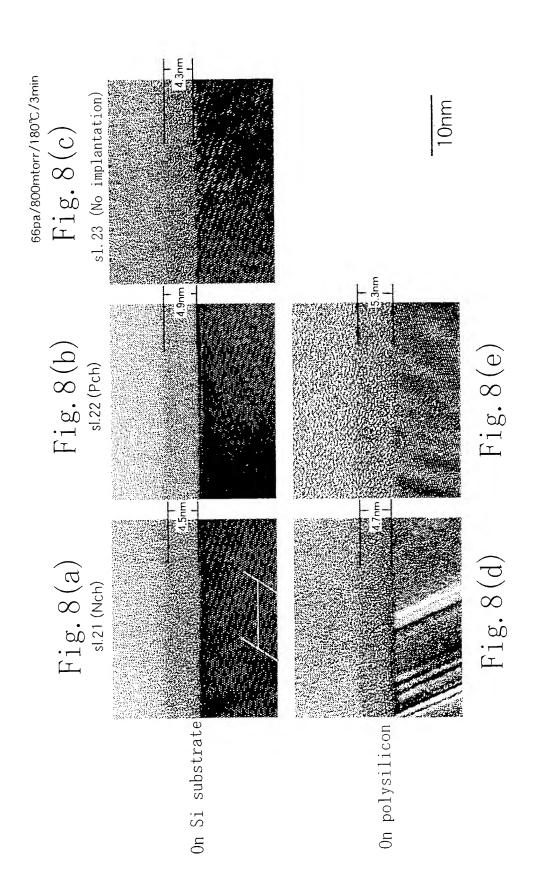




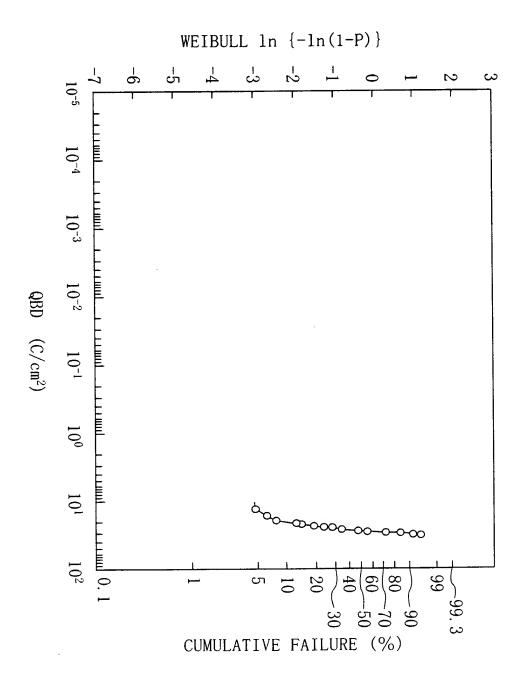


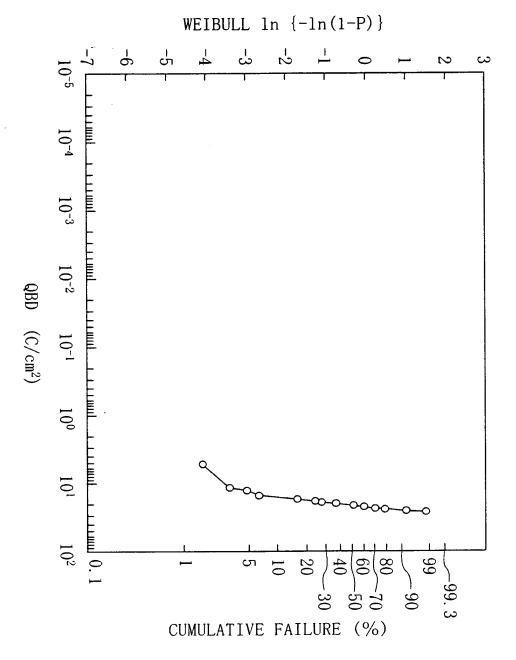




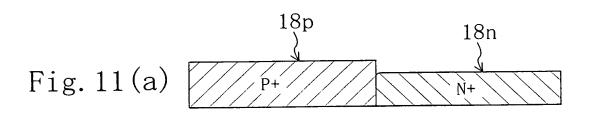


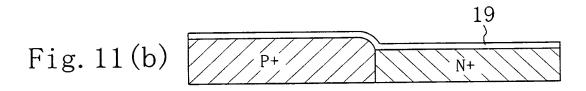


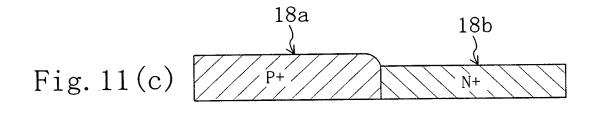


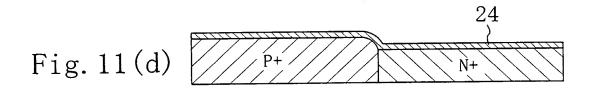


ìig. 10









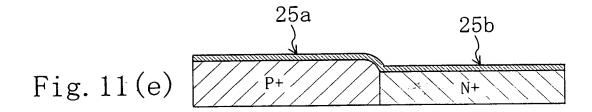
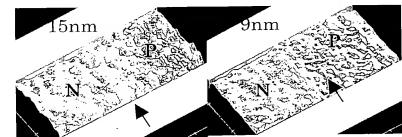


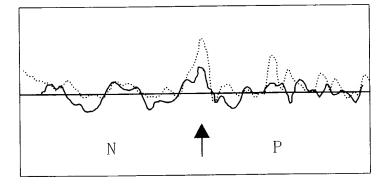
Fig. 12(a)

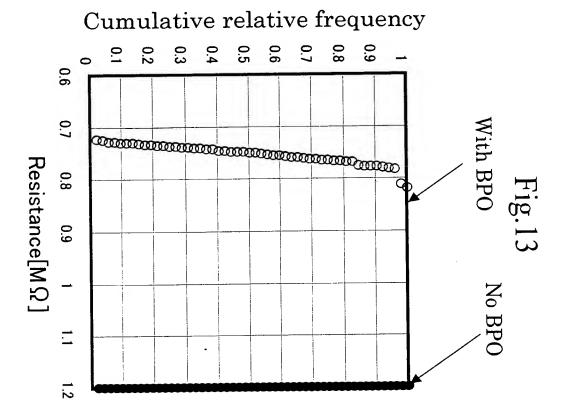


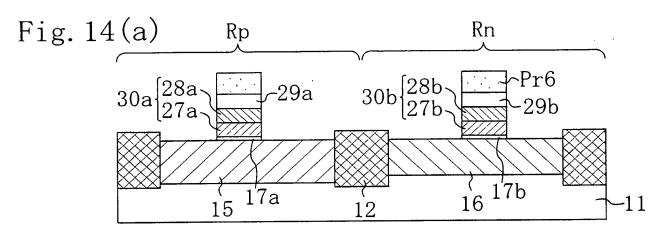
(1) No plasma oxidation (2) With plasma oxidation

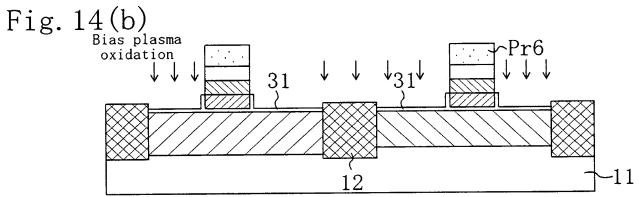
Fig. 12(b)

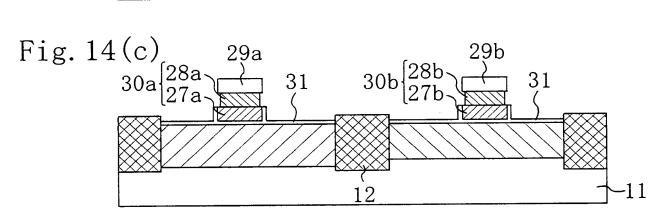
——— With BPO No BPO











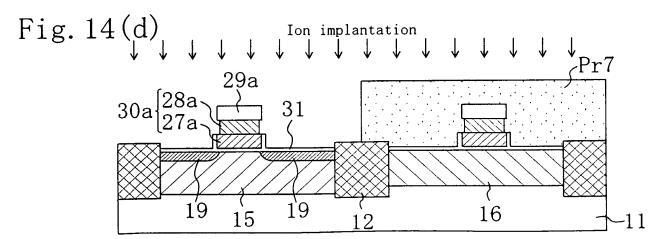


Fig. 15(a)

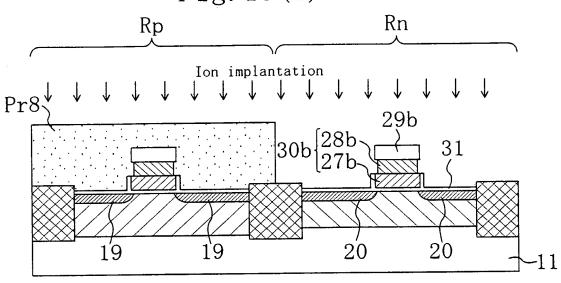


Fig. 15(b)

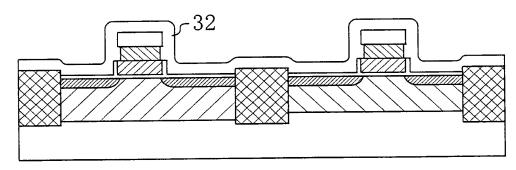


Fig. 15(c)

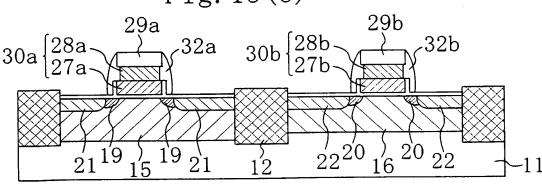
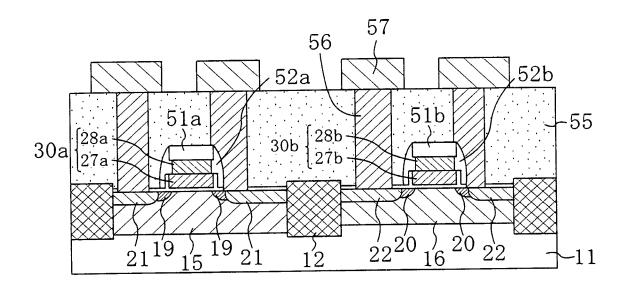
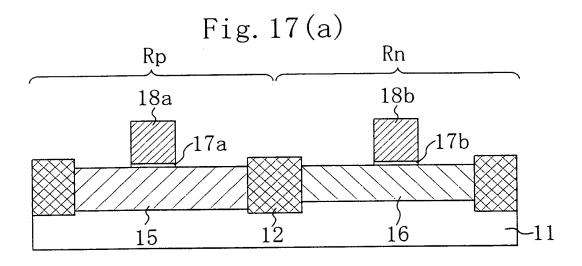
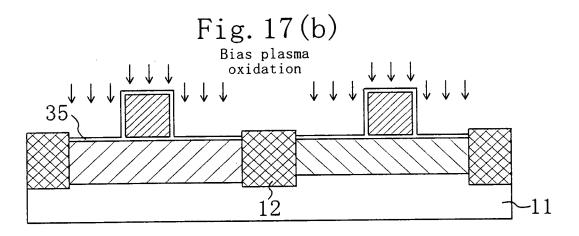


Fig. 16







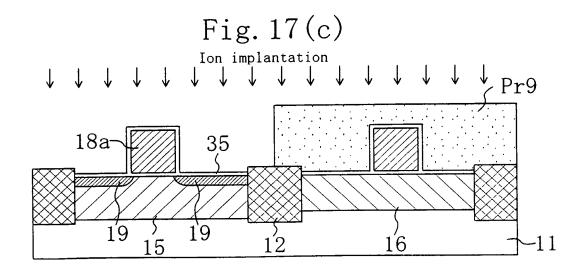
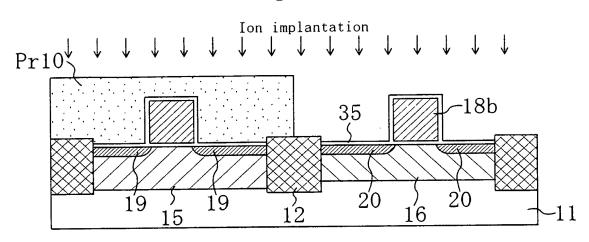
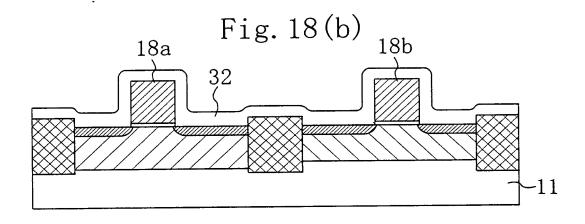
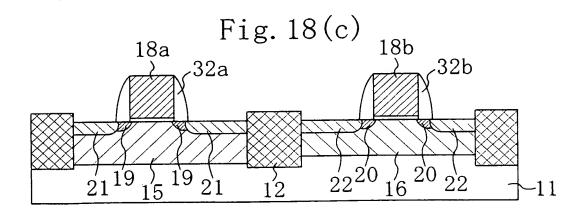


Fig. 18(a)







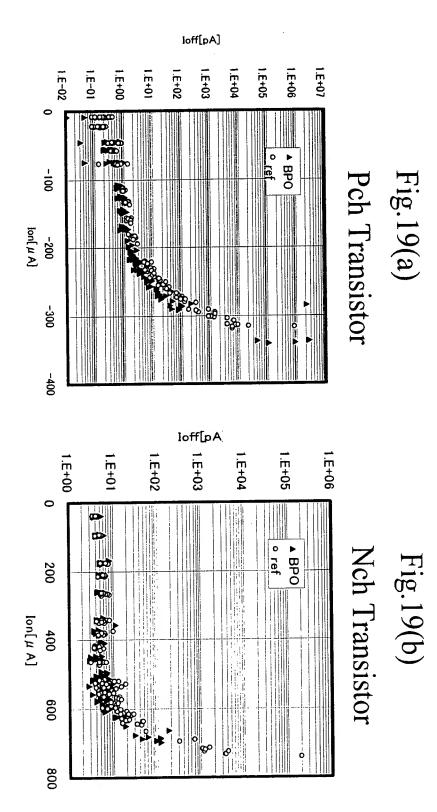


Fig. 20(a) 4,3 44

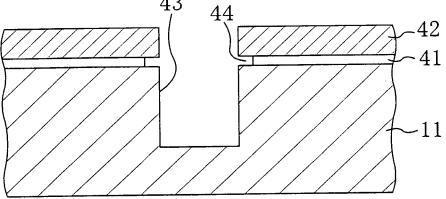


Fig. 20(b)

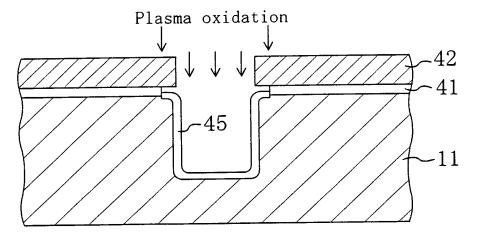
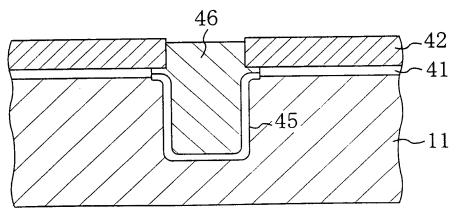
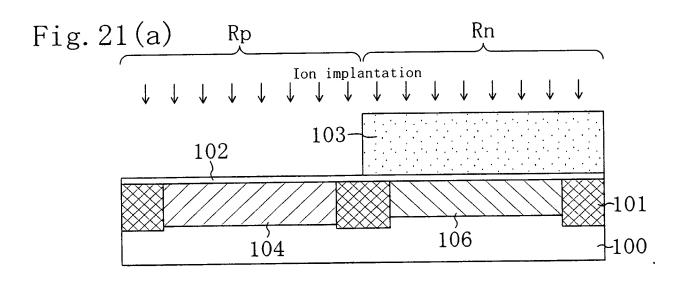
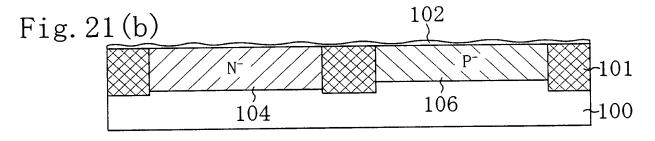
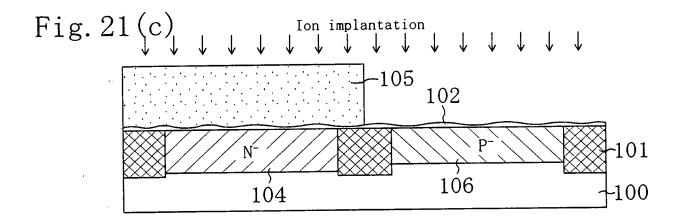


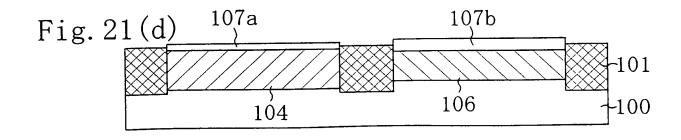
Fig. 20(c)

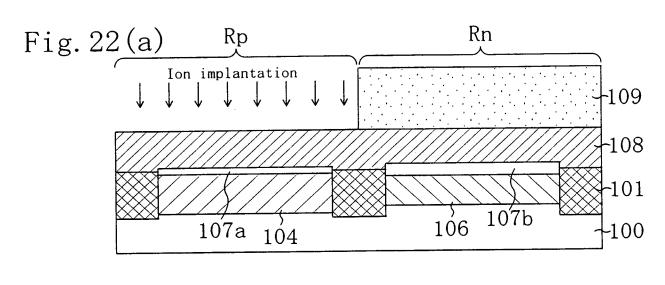


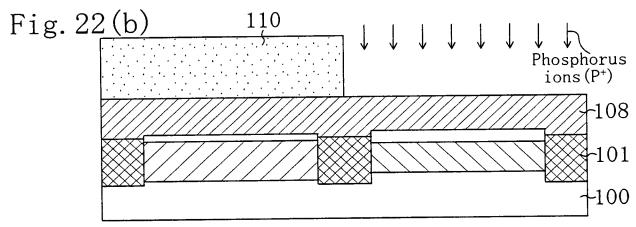


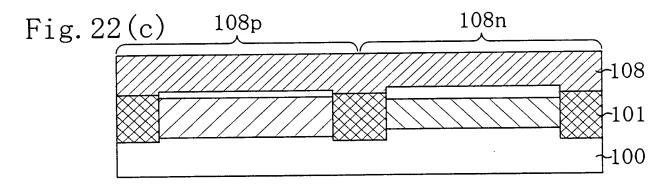


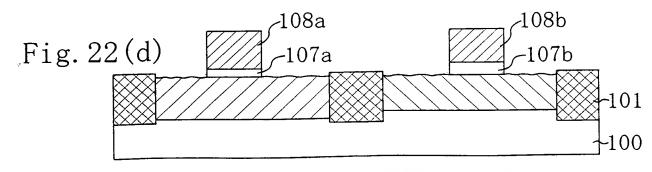












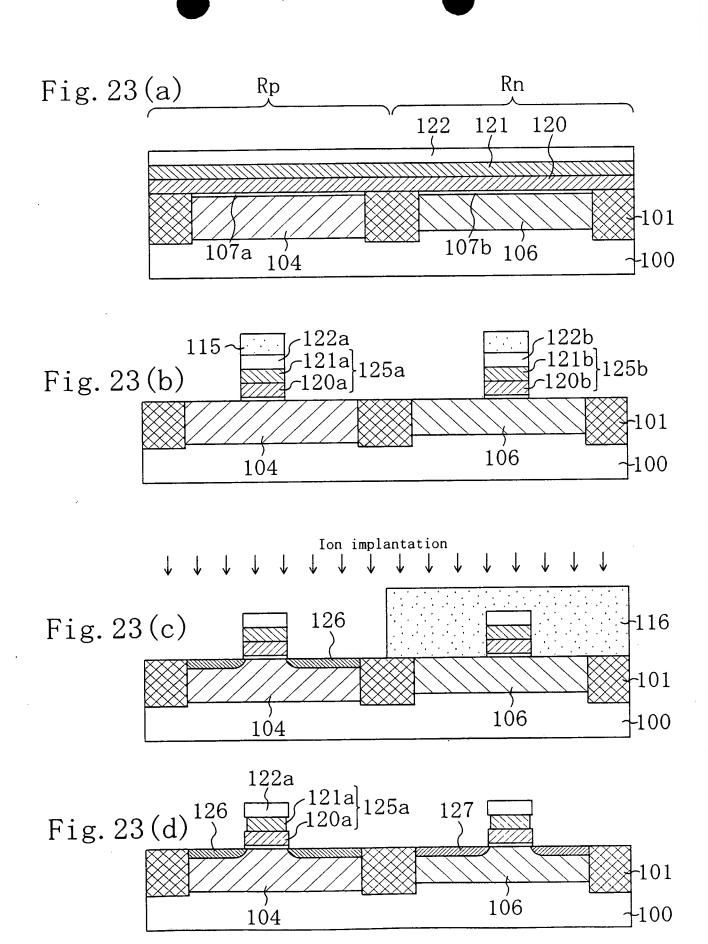


Fig. 24(a)

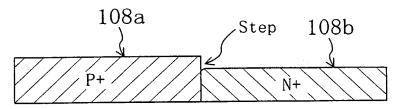


Fig. 24(b)

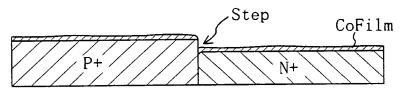


Fig. 24(c)

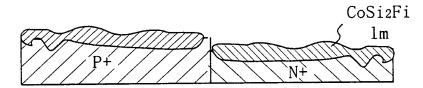


Fig. 25

